## Notice of References Cited Application/Control No. 10/750,024 Examiner James A. Dudek U.S. PATENT DOCUMENTS Applicant(s)/Patent Under Reexamination CHEN ET AL. Page 1 of 1

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2005/0046321 A1	03-2005	Suga et al.	313/112
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